Abstract

A testing module in the life cycle of a software development plays a crucial role for its development and its successful deployment using the defined cases. For this previous practitioner incorporated data mining techniques to reduce the number of test cases. During the software development process appropriate selection of unit tests is vital when many unit tests exist. Poor test selection may lead to Faults. This is true when the application is large and many developers are involved with some tests in which the developer can be unfamiliar and non-obvious relationships between application code and test code may be extant. By the application of association rule mining and the unit test selection process and with extant selection techniques by comparison, Researchers facilitates a quantitative analysis of the advantages of heuristic and its disadvantages for the development where process patterns are stable. In test case generation technique data mining knowledge engineering area plays a vital role where the algorithm are capable of analyzing based on the pattern description such that the effective and accurate test cases can be generated, in this paper author presents a method to reduction the number of test suites by using mining methods thereby facilitating the mining from
Amalgamation of Automated Test Case Generation Techniques with Data Mining Techniques: A Survey

test cases. Here we are discussing about the Automated Test case Generation Techniques with Data Mining Techniques.

References

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**Index Terms**

Computer Science Software Engineering

**Keywords**

Software Engineering, Software Testing, data mining, test cases, data item, test suite, Weka, item set, classifier, Cluster, Automated, and Redundancy.